# TYPES 2N3707 THRU 2N3711, A5T3707 THRU A5T3711, A8T3707 THRU A8T3711 N-P-N SILICON TRANSISTORS

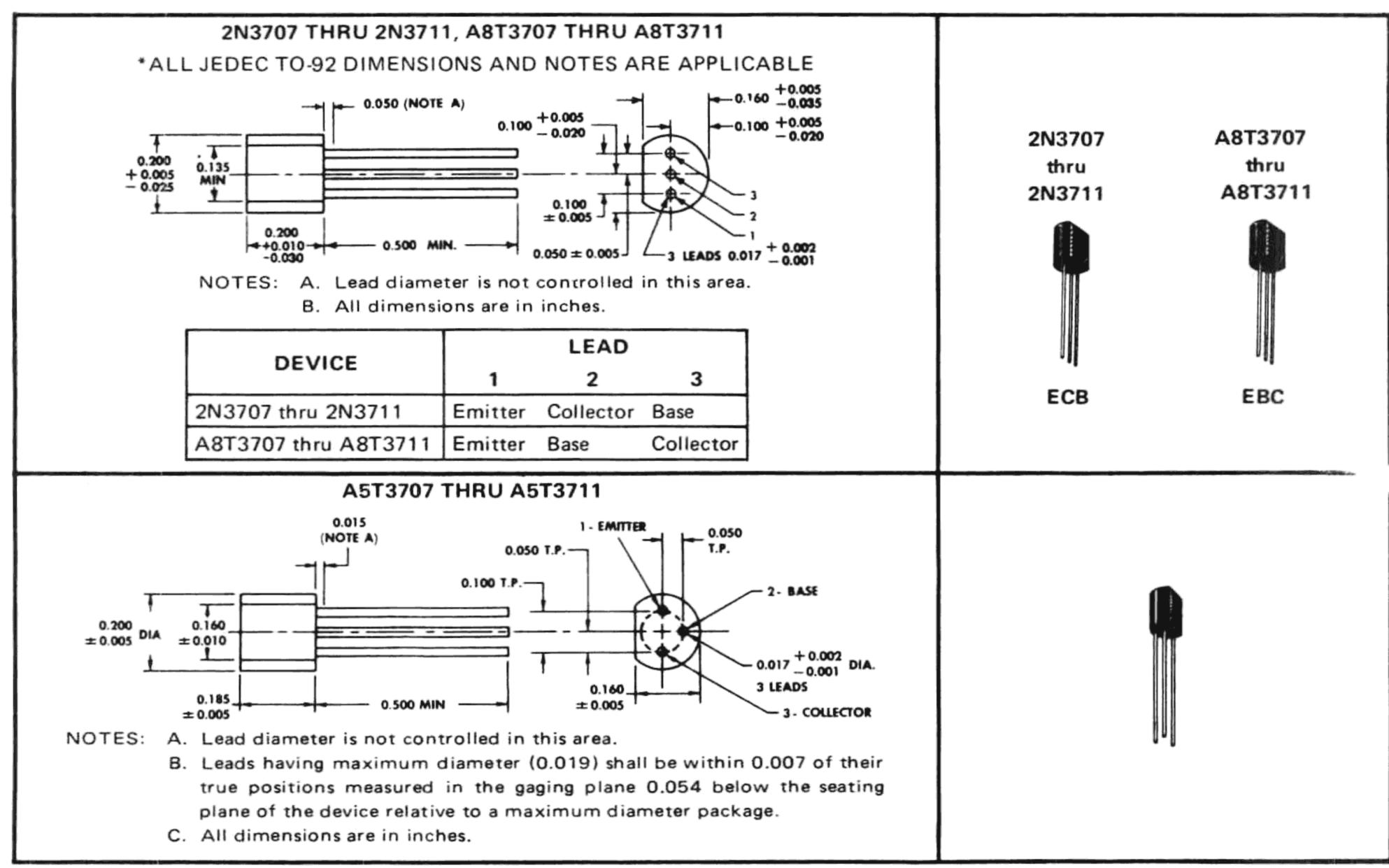
BULLETIN NO. DL-S 7311965, MARCH 1973

# SILECT<sup>†</sup> TRANSISTORS<sup>‡</sup>

- Ideal for Low-Level Amplifier Applications
- Rugged One-Piece Construction with In-Line Leads or Standard TO-18 100-mil
  Pin-Circle Configuration
- Recommended for Complementary Use with 2N4058 thru 2N4062, A5T4058 thru A5T4062, or A8T4058 thru A8T4062

#### mechanical data

These transistors are encapsulated in a plastic compound specifically designed for this purpose, using a highly mechanized process developed by Texas Instruments. The case will withstand soldering temperatures without deformation. These devices exhibit stable characteristics under high-humidity conditions and are capable of meeting MIL-STD-202C, Method 106B. The transistors are insensitive to light.



### absolute maximum ratings at 25°C free-air temperature (unless otherwise noted)

Collector-Base Voltage		 	30 V*
Collector-Emitter Voltage (See Note 1)		 	30 V*
Emitter-Base Voltage		 	6 V*
Continuous Collector Current			
Continuous Device Dissipation at (or below) 25°C Free-Air Temperature (See	e Note 2)	 	mW§
Ctorona Tomanoratura Donas		(300 65°C to 1	T M VV
Storage Temperature Range		 —65 C to 1	50 C
Lead Temperature 1/16 Inch from Case for 10 Seconds		 2	60 C

NOTES: 1. This value applies when the base-emitter diode is open-circuited.

- Derate the 625-mW rating linearly to 150°C free-air temperature at the rate of 5 mW/°C. Derate the 360-mW (JEDEC registered) rating linearly to 150°C free-air temperature at the rate of 2.88 mW/°C.
- \*The asterisk identifies JEDEC registered data for the 2N3707 through 2N3711 only. This data sheet contains all applicable registered data in effect at the time of publication.
- <sup>†</sup>Trademark of Texas Instruments
- ‡U.S. Patent No. 3,439,238
- § Texas Instruments guarantees this value in addition to the JEDEC registered value which is also shown.

**USES CHIP N21** 

# 2N3707 THRU 2N3711, A5T3707 THRU A5T3711, A8T3707 THRU A8T3711 N-P-N SILICON TRANSISTORS

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## \*electrical characteristics at 25°C free-air temperature

PARAMETER		TEST CONDITIONS		2N3707 A5T3707 A8T3707		2N3708 A5T3708 A8T3708		2N3709 A5T3709 A8T3709		2N3710 A5T3710 A8T3710		2N3711 A5T3711 A8T3711		UNIT
				V(BR)CEO	Collector-Emitter Breakdown Voltage	I <sub>C</sub> = 1 mA,	1 <sub>B</sub> = 0	30		30		30		30
Ісво	Collector Cutoff Current	V <sub>CB</sub> = 20 V,	IE = 0		100		100		100		100		100	nΑ
IEBO	Emitter Cutoff Current	V <sub>EB</sub> = 6 V,	I <sub>C</sub> = 0		100		100		100		100		100	nΑ
	Static Forward Current	V <sub>CE</sub> = 5 V,	I <sub>C</sub> = 100 μA	100	400									
hFE	Transfer Ratio	$V_{CE} = 5 V$ ,	$I_C = 1 \text{ mA}$			45	660	45	165	90	330	180	660	
V <sub>BE</sub>	Base-Emitter Voltage	$V_{CE} = 5 V$ ,	$I_C = 1 \text{ mA}$	0.5	1	0.5	1	0.5	1	0.5	1	0.5	1	V
V <sub>CE(sat)</sub>	Collector-Emitter Saturation Voltage	I <sub>B</sub> = 0.5 mA,	I <sub>C</sub> = 10 mA		1		1		1		1		1	V
h <sub>fe</sub>	Small-Signal	V <sub>CE</sub> = 5 V,	$I_C = 100  \mu A$ ,	100 55	550									
	Common-Emitter	f = 1 kHz		100										
	Forward Current Transfer Ratio	V <sub>CE</sub> = 5 V, f = 1 kHz	I <sub>C</sub> = 1 mA,			45	800	45	250	90	450	180	800	

### \*operating characteristics at 25°C free-air temperature

PARAMETER		TEST CONDITIONS	2N3707, A5T3707, A8T3707 UNI	UNIT
			MIN TYP MAX	
	E Averess Noise Eigure	$V_{CE} = 5 \text{ V}$ , $I_{C} = 100 \mu\text{A}$ , $R_{G} = 5 \text{ks}$	1.9 5 dB	
F Average Noise Figure	Noise Bandwidth = 15.7 kHz, See Note 3	3	ub	

NOTE 3: Average Noise Figure is measured in an amplifier with response down 3 dB at 10 Hz and 10 kHz and a high-frequency rolloff of 6 dB/octave.

#### THERMAL INFORMATION

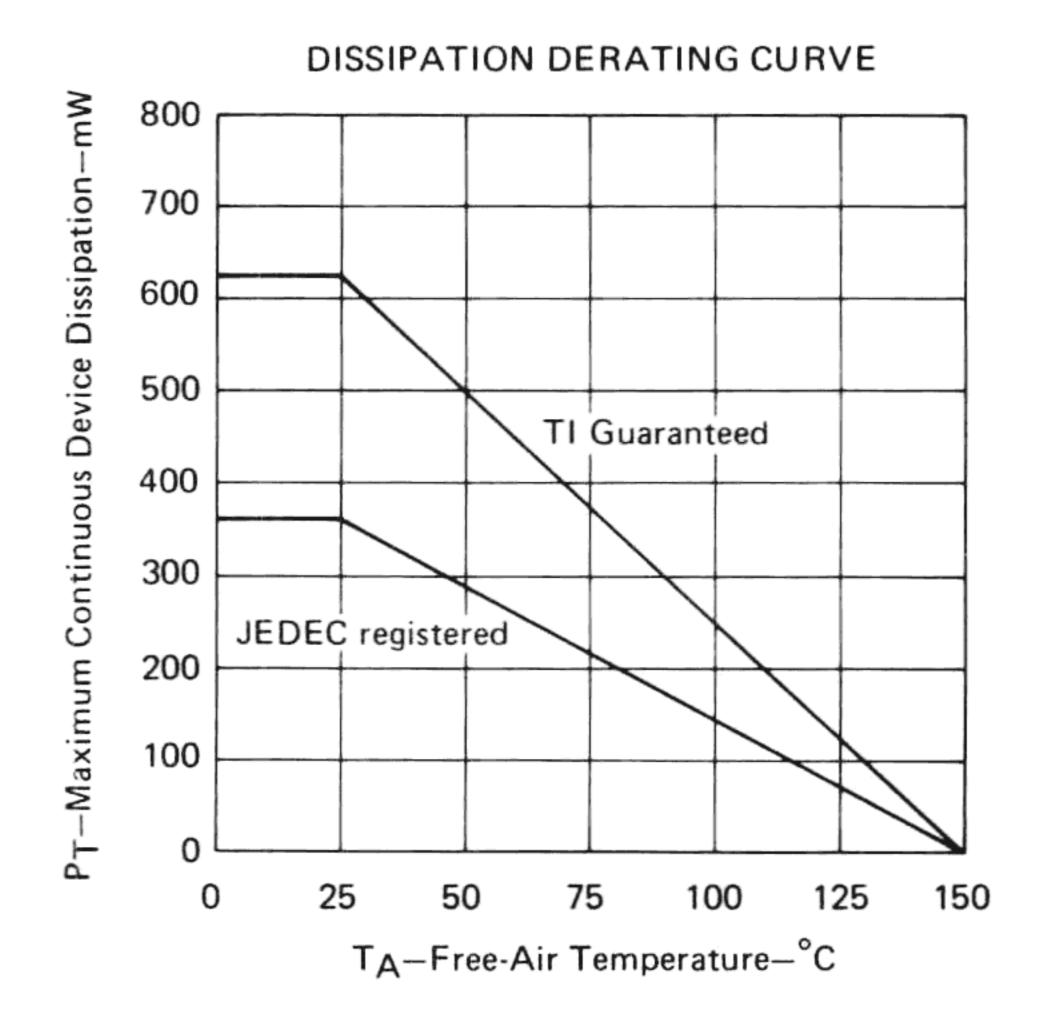


FIGURE 1

<sup>\*</sup>The asterisk identifies JEDEC registered data for 2N3707 through 2N3711 only.